

	Type	Hits	Search Text	DBs	Time Stamp
1	BRS	33	rosencwaig.in.	USPAT	2002/06/24 10:01
2	BRS	25	rosencwaig.in. and semiconductor	USPAT	2002/06/24 10:02
3	BRS	8	(rosencwaig.in. and semiconductor) and gas\$5	USPAT	2002/06/24 09:48
4	BRS	0	((rosencwaig.in. and semiconductor) and gas\$5) and microwave	USPAT	2002/06/24 09:49
5	BRS	0	((rosencwaig.in. and semiconductor) and gas\$5) and (reduce adj thickness)	USPAT	2002/06/24 09:49
6	BRS	7	((rosencwaig.in. and semiconductor) and gas\$5) and (thickness)	USPAT	2002/06/24 10:02
7	BRS	4	((((rosencwaig.in. and semiconductor) and gas\$5) and (thickness)) and (probe adj beam)	USPAT	2002/06/24 10:02
8	BRS	50	rosencwaig.in. or opsal.in.	USPAT	2002/06/24 10:01
9	BRS	4	((((rosencwaig.in. and semiconductor) and gas\$5) and (thickness)) and (thickness and (probe adj beam)))	USPAT	2002/06/24 10:03
10	BRS	30	((rosencwaig.in. or opsal.in.) and semiconductor) and (thickness and (probe adj beam))	USPAT	2002/06/24 10:03
11	BRS	8	((((rosencwaig.in. or opsal.in.) and semiconductor) and (thickness and (probe adj beam)))) and gas\$4	USPAT	2002/06/24 14:43
12	BRS	5488	semiconductor and wafer and microwave	USPAT; EPO; JPO; DERWENT	2002/06/24 14:43
13	BRS	20	(semiconductor and wafer and microwave) and (thickness and (probe adj beam))	USPAT; EPO; JPO; DERWENT	2002/06/24 17:16
14	BRS	40	(rosencwaig.in. or opsal.in.) and semiconductor	USPAT	2002/06/24 16:34
15	BRS	36	((rosencwaig.in. or opsal.in.) and semiconductor) and (probe adj beam)	USPAT	2002/06/30 19:29
16	IS&R	7	((("5798837") or ("5449411") or ("5439596") or ("5306671") or ("5261965") or ("5049816") or ("3887392"))).PN.	USPAT	2002/06/24 17:21
17	BRS	6	((("5798837") or ("5449411") or ("5439596") or ("5306671") or ("5261965") or ("5049816") or ("3887392"))).PN.) and microwave	USPAT	2002/06/24 17:29
18	BRS	5	(((((("5798837") or ("5449411") or ("5439596") or ("5306671") or ("5261965") or ("5049816") or ("3887392"))).PN.) and microwave) and gas\$5	USPAT	2002/06/24 17:30
19	BRS	13	spectrophotometer and ellipsometer and (probe adj beam)	USPAT; EPO; JPO; DERWENT	2003/09/04 16:13
20	BRS	1	(spectrophotometer and ellipsometer and (probe adj beam)) and cleaning	USPAT; EPO; JPO; DERWENT	2002/06/30 19:32
21	BRS	67	ellipsometer and (probe adj beam)	USPAT; EPO; JPO; DERWENT	2002/06/30 19:32

Type	Hits	Search Text	DBs	Time Stamp
22 BRS	5	(ellipsometer and (probe adj beam)) and cleaning	USPAT; EPO; JPO; DERWENT	2002/06/30 19:32
23 BRS	30	(rotating adj compensator) and (rotating adj analyzer)	USPAT; EPO; JPO; DERWENT	2002/06/30 19:51
24 BRS	12	((rotating adj compensator) and (rotating adj analyzer)) and (probe adj beam)	USPAT; EPO; JPO; DERWENT	2002/12/15 20:33
25 BRS	9	(carbon adj dioxide adj pellets) and semiconductor and wafer	USPAT; EPO; JPO; DERWENT	2002/07/01 03:08
26 IS&R	1	("5261965").PN.	USPAT	2002/07/01 04:29
27 BRS	1	((("5261965").PN.) and microwave	USPAT	2002/07/01 03:17
28 BRS	1	((("5261965").PN.) and microwave) and heat	USPAT	2002/07/01 03:17
29 BRS	1	5261965.pn. and vacuum	USPAT	2002/07/01 05:13
30 BRS	1	5798837.pn. and polychromatic	USPAT	2002/07/01 05:14
31 BRS	1	5798837.pn. and uv	USPAT	2002/07/01 05:14
32 BRS	0	((rotating adj compensator) and (rotating adj analyzer)) and (probe adj beam) and transport	USPAT; EPO; JPO; DERWENT	2002/12/15 20:34
33 BRS	1927	356/237.2-237.5,369,432.ccls.	USPAT	2003/09/04 16:02
34 BRS	1391	356/237.2-237.5,369,432.ccls. and @ad<19980928	USPAT	2003/09/04 16:04
35 BRS	95	(356/237.2-237.5,369,432.ccls. and @ad<19980928) and cleaning	USPAT	2003/09/04 16:04
36 BRS	0	((356/237.2-237.5,369,432.ccls. and @ad<19980928) and cleaning) AND spectrophotometer and ellipsometer and (probe adj beam)	USPAT; EPO; JPO; DERWENT	2003/09/04 16:14
37 BRS	2	((356/237.2-237.5,369,432.ccls. and @ad<19980928) and cleaning) AND spectrophotometer and (probe adj beam)	USPAT	2003/09/04 16:14
38 BRS	3	((356/237.2-237.5,369,432.ccls. and @ad<19980928) and cleaning) and (probe adj beam)	USPAT	2004/07/23 09:40
39 IS&R	2	((("5798837") or ("5261965")).PN.	USPAT	2004/07/23 08:12
40 BRS	2	(optical adj inspection adj system) and (cleaning adj system)	USPAT; US-PGPUB	2004/07/23 09:17
41 BRS	135	(spectrophotometer or ellipsometer) and (cleaning adj system)	USPAT; US-PGPUB	2004/07/23 08:19
42 BRS	50	((spectrophotometer or ellipsometer) and (cleaning adj system)) and @ad<=19980928	USPAT; US-PGPUB	2004/07/23 09:17
43 BRS	11	((((spectrophotometer or ellipsometer) and (cleaning adj system)) and @ad<=19980928) and (semiconductor or wafer)	USPAT; US-PGPUB	2004/07/23 09:14

	Type	Hits	Search Text	DBs	Time Stamp
44	IS&R	1	("6714884").PN.	USPAT	2004/07/23 09:14
45	IS&R	0	("1andclean\$4").PN.	USPAT	2004/07/23 09:14
46	BRS	1	("6714884").PN.) and clean\$4	USPAT	2004/07/23 09:15
47	BRS	0	(optical adj inspection adj system) and (cleaning adj system)	EPO, JPO, DERWENT	2004/07/23 09:17
48	BRS	1	((spectrophotometer or ellipsometer) and (cleaning adj system)) and @ad<=19980928	EPO, JPO, DERWENT	2004/07/23 09:17
49	BRS	27	((356/237.2-237.5,369,432.ccls. and @ad<19980928) and clean\$4) and (spectrophotometer or ellipsometer)	USPAT; US-PGPUB	2004/07/23 10:00
50	BRS	19	((356/237.2-237.5,369,432.ccls. and @ad<19980928) and clean\$4) and (spectrophotometer or ellipsometer)) and (semiconductor or wafer)	USPAT; US-PGPUB	2004/07/23 10:00
51	BRS	33	((356/237.1-237.5,369,432.ccls. and @ad<19980928) and clean\$4) and (spectrophotometer or ellipsometer)	USPAT; US-PGPUB	2004/07/23 10:00
52	BRS	21	((356/237.1-237.5,369,432.ccls. and @ad<19980928) and clean\$4) and (spectrophotometer or ellipsometer)) and (semiconductor or wafer)	USPAT; US-PGPUB	2004/07/23 10:00
53	BRS	2	((356/237.1-237.5,369,432.ccls. and @ad<19980928) and clean\$4) and (spectrophotometer or ellipsometer)) and (semiconductor or wafer)) not (((356/237.2-237.5,369,432.ccls. and @ad<19980928) and clean\$4) and (spectrophotometer or ellipsometer)) and (semiconductor or wafer))	USPAT; US-PGPUB	2004/07/23 10:01
54	IS&R	8	(("3,887,392") or ("5,261,965") or ("5,306,671") or ("5,316,970") or ("5,439,596") or ("5,449,411") or ("5,798,837") or ("6,325,078")).PN.	USPAT	2004/07/23 10:02